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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/601,553	06/24/2003	Tohru Kohda	03599.000064.	7757
5514	7590 02/18/2005		EXAMINER	
FITZPATRICK CELLA HARPER & SCINTO 30 ROCKEFELLER PLAZA NEW YORK, NY 10112			KIM, PETER B	
			ART UNIT	PAPER NUMBER
			2851	
			DATE MAILED: 02/18/2005	5

Please find below and/or attached an Office communication concerning this application or proceeding.

Application No.	Applicant(s)			
10/601,553	KOHDA ET AL.			
Examiner	Art Unit			
Peter B. Kim	2851			
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d on 23 December 2004.				
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ce under <i>Ex parte Quayle</i> , 1935 C	.D. 11, 453 O.G. 213.			
Claim(s) <u>1-22</u> is/are pending in the application.				
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4) ☐ Interview	w Summary (PTO-413)			
TO-948) Paper N	w Summary (PTO-413) o(s)/Mail Date of Informal Patent Application (PTO-152)			
	Examiner Peter B. Kim ication appears on the cover sheet OR REPLY IS SET TO EXPIRE 3 CATION. of 37 CFR 1.136(a). In no event, however, may unication. Oldays, a reply within the statutory minimum of attutory period will apply and will expire SIX (6) M will, by statute, cause the application to become fler the mailing date of this communication, ever and on 23 December 2004. Oblimation is non-final. If or allowance except for formal mace under Ex parte Quayle, 1935 Complication. The withdrawn from consideration. The withdrawn from consideration are rejected. The examiner is accepted or by objected to be accepted or by objected to be accepted or by the Examiner. The examiner is required if the drawing of the correction is required if the drawing of the Examiner. The for foreign priority under 35 U.S.C. documents have been received.			

DETAILED ACTION

Applicant's arguments filed on Dec. 23, 2004 have been fully considered.

Claim Rejections - 35 USC § 102

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

(a) the invention was known or used by others in this country, or patented or described in a printed publication in this or a foreign country, before the invention thereof by the applicant for a patent.

Claims 7, 8, 10-12, and 19-22 are rejected under 35 U.S.C. 102(a) as being anticipated by Nishi (6,522,386).

Nishi discloses a scanning exposure apparatus and method comprising an illumination optical system (1, 7) for illuminating a pattern on a mask (R) using arc-shaped light (col. 26, lines 3-11); a projection optical system (PL); a mask stage (8, 10), a plate stage (TB), the scanning exposure apparatus scanning the mask stage and plate stage synchronously relative to the projection optical system, a mask support for supporting periphery of the mask (Fig. 1), a plate stage tilt mechanism (ZAC, col. 9, line 49-57) for arranging a surface of the plate, wherein the mask deforms due to its own weight from the peripheral support. Nishi also discloses measuring a focus position, identifying an image plane position and calculating tilt angle for tilting the plate and correcting a tilt of the plate and exposing the actual mask (col. 9, lines 58-67). Nishi discloses the mask supported at two sides perpendicular to a scan direction (Fig. 1), where the plate is tilted at the stage stool (col. 9, lines 49-57), correcting projection magnification in a direction orthogonal to a scan direction and a stage control mechanism for scanning at a speed ratio corresponding to a projection magnification (col. 1, lines 38-50).

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Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claims 1, 2, 4-6, 13, 14, and 16-18 are rejected under 35 U.S.C. 103(a) as being unpatentable over Nishi in view of Ota et al. (Ota).

Nishi discloses a scanning exposure apparatus and method comprising an illumination optical system (1, 7) for illuminating a pattern on a mask (R) using arc-shaped light (col. 26, lines 3-11); a projection optical system (PL); a mask stage (8, 10), a plate stage (TB), the scanning exposure apparatus scanning the mask stage and plate stage synchronously relative to the projection optical system, a mask support for supporting periphery of the mask (Fig. 1), a plate stage tilt mechanism (ZAC, col. 9, line 49-57) for arranging a surface of the plate, wherein the mask deforms due to its own weight from the peripheral support. Nishi also discloses measuring a focus position, identifying an image plane position and calculating tilt angle for tilting the plate and correcting a tilt of the plate and exposing the actual mask (col. 9, lines 58-67). Nishi discloses the mask supported at two sides perpendicular to a scan direction (Fig. 1), where the plate is tilted at the stage stool (col. 9, lines 49-57), correcting projection magnification in a direction orthogonal to a scan direction and a stage control mechanism for scanning at a speed ratio corresponding to a projection magnification (col. 1, lines 38-50).

However, Nishi does not disclose tilting of the mask stage. Ota discloses in col. 11, lines 33-44, tilting of the mask stage. Therefore, it would have been obvious to one of ordinary skill

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in the art at the time of the invention to provide tilting of the mask as taught by Ota to the invention of Nishi in order to provide correction for deviation in the focus error as taught by Nishi in col. 9, lines 58-67.

Allowable Subject Matter

Claims 3, 9, and 15 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

None of the prior art of record teaches the mask support mechanism supporting the mask only at two sides parallel to a scan direction in combination with the limitations of claims 1, 7 or 13.

Response to Arguments

Applicant's arguments with respect to claims 1, 2, 4-8, 10-14, and 16-22 have been considered but are most in view of the new ground(s) of rejection.

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Peter B. Kim whose telephone number is (571) 272-2120. The examiner can normally be reached on 8:00 AM - 5:30 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Judy Nguyen can be reached on (571) 272-2258. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Peter B. Kim
Primary Examiner

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February 14, 2005